1.

Record Nr.	UNINA9910872857603321
Titolo	1998 International Conference on Indium Phosphide and Related Materials
Pubbl/distr/stampa	[Place of publication not identified], : IEEE, 1998
Descrizione fisica	1 online resource (800 pages)
Disciplina	621.38152
Soggetti	Indium phosphide
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Sommario/riassunto	The papers included in this leading international conference examine test structures for microelectronic devices, their recent progress and future directions. Included is a detailed treatment of current developments in microelectronic test structure research, implementation, and applications. Also addressed are advances in device characterization, such as increased miniaturization, reduced operating voltages and reduced power requirements through improved measurement and test techniques. Topics highlighted include: Process Characterization, Dimensional Measurements, Interconnection, Material Characterization, Reliability, Device Characterization, and Statistics.

2.

Record Nr.	UNINA9910139624703321
Titolo	2011 Compound Semiconductor Week and 23rd International Conference on Indium Phosphide and Related Materials
Pubbl/distr/stampa	[Place of publication not identified], : IEEE, 2011
ISBN	9783800733569 3800733560
Descrizione fisica	1 online resource : illustrations
Disciplina	621.38152
Soggetti	Electronics - Materials Indium phosphide
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph